



























Exams for group M17-416

Thu, 29 Nov	08:30 — 10:05	TEST	Law and Economics of Scientific Projects and Units  Nurahov N.N.  V-404
Tue, 25 Dec	10:15 — 11:50	ATT	Modern Micro and Nanotechnologies  Veselov D.S.  D-418
Tue, 25 Dec	12:45 — 14:20	TEST	Principles of Nuclear Technologies  Apse V.A.  B-100
Wed, 26 Dec	08:30 — 10:05	ATT	Computer Technology: Design and Programming of Microprocessor Systems  Shagurin I.I.  D-303
Wed, 26 Dec	11:05 — 12:40	ATT	Reliability and Radiation Resistance of Microelectronic Devices and Systems  Zebrev G.I.  D-408
Thu, 27 Dec	10:15 — 11:50	TEST	Computer Technology  Krasavin A.V.  V-116
Thu, 27 Dec	11:55 — 13:30	TEST	Practical Training (Research Work)  Samotaev N.N.  dep.27
Fri, 28 Dec	12:00 — 14:20	TEST	Legal and International Aspects of Nonproliferation and Nuclear Materials Safety.  Bogdanovich R.B., Baratova A.A., Kulikov E.G.  B-100
Fri, 28 Dec	14:30 — 16:05	ATT	Design of Integrated Circuits and Systems-on-Chip (SOC)  Bakerenkov A.S.  D-303
Thu, 10 Jan	09:00 — 13:00	EXAM	Design of Integrated Circuits and Systems-on-Chip (SOC)  Bakerenkov A.S.  D-303
Mon, 14 Jan	09:00 — 13:00	EXAM	Reliability and Radiation Resistance of Microelectronic Devices and Systems  Zebrev G.I.  D-408
Fri, 18 Jan	09:00 — 13:00	EXAM	Modern Micro and Nanotechnologies  Veselov D.S.  D-303
Tue, 22 Jan	09:00 — 13:00	EXAM	Computer Technology: Design and Programming of Microprocessor Systems  Shagurin I.I.  D-303